

| L Number | Hits | Search Text   | DB  | Time stamp          |
|----------|------|---|---|---------------------|
| 1        | 85   | jtag same non-jtag  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/27<br>18:54 |
| 2        | 1    | configur\$6 near5 non-jtag                                  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/27<br>18:56 |
| 3        | 10   | configur\$6 same (jtag same non-jtag)                       | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/27<br>19:07 |
| 4        | 0    | 710/\$.ccls. and (configur\$6 same (jtag same non-jtag))    | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/27<br>19:08 |
| 5        | 5    | 714/\$.ccls. and (configur\$6 same (jtag same non-jtag))    | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/27<br>19:08 |
| 6        | 2    | 716/\$.ccls. and (configur\$6 same (jtag same non-jtag))    | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/27<br>19:08 |
| 7        | 0    | 713/\$.ccls. and (configur\$6 same (jtag same non-jtag))    | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/27<br>19:08 |
| 8        | 0    | 326/\$.ccls. and (configur\$6 same (jtag same non-jtag))    | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/27<br>19:08 |
| 9        | 1    | 711/\$.ccls. and (configur\$6 same (jtag same non-jtag))    | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/27<br>19:31 |
| 10       | 262  | bypass\$3 with boundary adj scan                            | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/27<br>19:32 |
| 11       | 9    | (jtag same non-jtag) and (bypass\$3 with boundary adj scan) | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/27<br>19:32 |


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